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PECITATION			17524-728	09/9	09/944,063			
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Se	4,543,479	9/24/85	Kato	250	327.2			
50	4,582,989	4/15/86	Agano	250	327.2			
Se	4,973,134	11/27/90	Finkenzeller, et al.	250	327.2			
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Se	5,988,802	11/23/99	Pawlowski, Jr., et al.	347	86			
se	6,005,911	12/21/99	Cheung	378	37			
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			17524-728 09/944,063					
			APPLICANT Christopher R. Mitchell					
			FILING DATE 8/30/2001 GROUP 2878					
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	V1014 684 A3	28/6/2000	ЕРО	H04N	1/191	Ø		
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			APPLICANT Mitchell et al.					
			FILING DATE 08/30/2001 GROUP 2878					
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			Kavajiri					
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	/ OTHER DO	CUMENTS (Including Author, Title, Date,	Pertinent	t Pages, Etc.)			
Se	Lee et al., "A 3E Symposium, pp.	X-ray Micro 19.37-19.40	tomographic system with CMOS (XP002231401), Oct 15-20, 2000	Image S	ensor", <u>Nuclear Sci</u>	ence		
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.